

THYRISTORS

Also available to BS9341-F083

Silicon thyristors in metal envelopes, intended for use in power control applications in general, and lighting control (in a.c. controller circuit) up to 2,5 kW in particular. A feature of the thyristors is their high surge rating.

The series consists of reverse polarity types (anode to stud) identified by a suffix R: BTW40-400R to 800R.

QUICK REFERENCE DATA

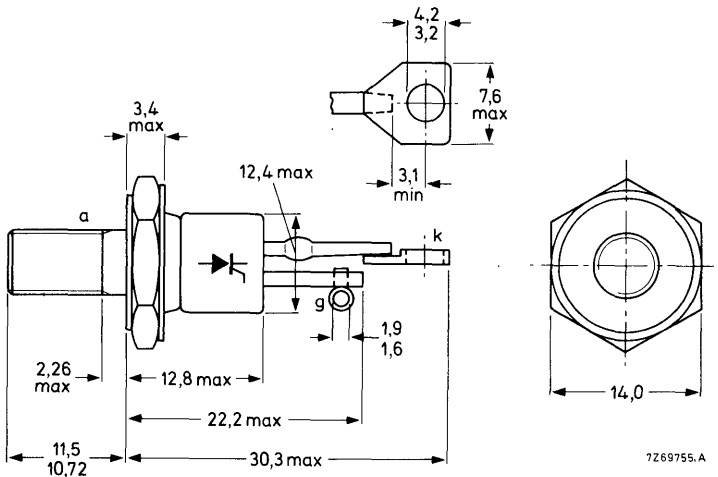
	V_{DRM}/V_{RRM}	BTW40-400R	600R	800R
Repetitive peak voltages	max.	400	600	800 V
Average on-state current	$I_T(AV)$	max.	20 A	
R.M.S. on-state current	$I_T(RMS)$	max.	32 A	
Non-repetitive peak on-state current	I_{TSM}	max.	400 A	

MECHANICAL DATA

Dimensions in mm

Fig. 1 TO-48: with metric M6 stud ($\phi 6$ mm); e.g. BTW40-400R.

Types with $\frac{1}{4}$ in x 28 UNF stud ($\phi 6,35$ mm) are available on request. These are indicated by the suffix U: e.g. BTW40-400RU.



Net mass: 14 g
 Diameter of clearance hole: max. 6,5 mm
 Accessories supplied on request: 56264A
 (mica washer, insulating ring, soldering tag)

Torque on nut: min. 1,7 Nm (17 kg cm)
 max. 3,5 Nm (35 kg cm)

Supplied with the device:
 1 nut, 1 lock washer
 Nut dimensions across the flats:
 M6: 10 mm
 $\frac{1}{4}$ in x 28 UNF: 11,1 mm

RATINGS

Limiting values in accordance with the Absolute Maximum System (IEC 134)

Anode to cathode

		BTW40-400R	600R	800R
Non-repetitive peak voltages ($t \leq 10$ ms)	V_{DSM}/V_{RSM}	max. 400	600	800 V
Repetitive peak voltages	V_{DRM}/V_{RRM}	max. 400	600	800 V
Crest working voltages	V_{DWM}/V_{RWM}	max. 300	400	600 V *
Average on-state current (averaged over any 20 ms period) up to $T_{mb} = 85$ °C	$I_T(AV)$	max.	20	A
R.M.S. on-state current	$I_T(RMS)$	max.	32	A
Repetitive peak on-state current	I_{TRM}	max.	200	A
Non-repetitive peak on-state current; $t = 10$ ms; half sine-wave; $T_j = 125$ °C prior to surge; with reapplied V_{RWMmax}	I_{TSM}	max.	400	A
I^2t for fusing ($t = 10$ ms)	I^2t	max.	800	A ² s
Rate of rise of on-state current after triggering with $I_G = 400$ mA to $I_T = 60$ A; $dI_G/dt = 0,4$ A/ μ s	dI_T/dt	max.	100	A/ μ s

Gate to cathode

Reverse peak voltage	V_{RGM}	max.	10	V
Average power dissipation (averaged over any 20 ms period)	$P_G(AV)$	max.	1	W
Peak power dissipation	P_{GM}	max.	5	W

Temperatures

Storage temperature	T_{stg}	-55 to + 125	°C
Junction temperature	T_j	max.	125 °C

THERMAL RESISTANCE

From junction to mounting base	$R_{th j-mb}$	=	1	°C/W
From mounting base to heatsink with heatsink compound	$R_{th mb-h}$	=	0,2	°C/W
Transient thermal impedance ($t = 1$ ms)	$Z_{th j-mb}$	=	0,1	°C/W

OPERATING NOTE

The terminals should neither be bent not twisted; they should be soldered into the circuit so that there is no strain on them.

During soldering the heat conduction to the junction should be kept to a minimum.

* To ensure thermal stability: $R_{th j-a} < 6,5$ °C/W (d.c. blocking) or < 13 °C/W (a.c.). For smaller heatsinks T_{jmax} should be derated. For a.c. see Fig. 3.

CHARACTERISTICS

Anode to cathode

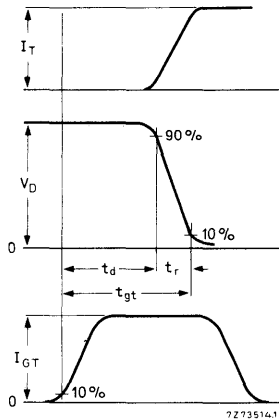
On-state voltage $I_T = 50 \text{ A}; T_j = 25 \text{ }^\circ\text{C}$	V_T	<	2,1 V *
Rate of rise of off-state voltage that will not trigger any device; exponential method; $V_D = 2/3 V_{DRMmax}; T_j = 125 \text{ }^\circ\text{C}$	dV_D/dt	<	100 V/ μs
Reverse current $V_R = V_{RWMmax}; T_j = 125 \text{ }^\circ\text{C}$	I_R	<	3 mA
Off-state current $V_D = V_{DWMmax}; T_j = 125 \text{ }^\circ\text{C}$	I_D	<	3 mA
Latching current; $T_j = 25 \text{ }^\circ\text{C}$	I_L	<	150 mA
Holding current; $T_j = 25 \text{ }^\circ\text{C}$	I_H	<	75 mA

Gate to cathode

Voltage that will trigger all devices $V_D = 6 \text{ V}; T_j = 25 \text{ }^\circ\text{C}$	V_{GT}	>	1,5 V
Voltage that will not trigger any device $V_D = V_{DRMmax}; T_j = 125 \text{ }^\circ\text{C}$	V_{GD}	<	200 mV
Current that will trigger all devices $V_D = 6 \text{ V}; T_j = 25 \text{ }^\circ\text{C}$	I_{GT}	>	75 mA

Switching characteristics

Gate-controlled turn-on time ($t_{gt} = t_d + t_r$) when switched from $V_D = V_{DWMmax}$ to $I_T = 100 \text{ A}; I_{GT} = 400 \text{ mA}; dI_G/dt = 1 \text{ A}/\mu\text{s}; T_j = 25 \text{ }^\circ\text{C}$	t_{gt}	<	1 μs
	t_r	<	0,5 μs



Gate-controlled turn-on time definition

*Measured under pulse conditions to avoid excessive dissipation.

7272517

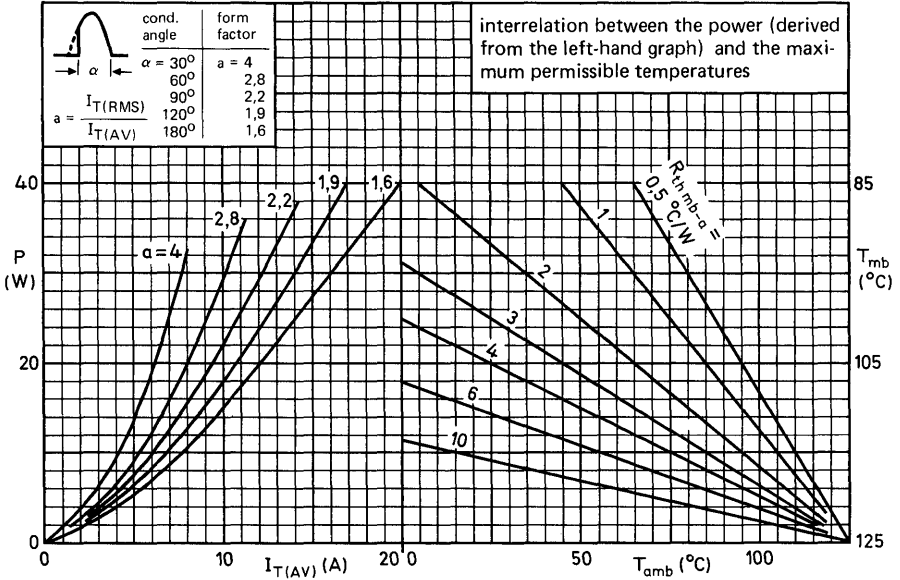


Fig. 2.

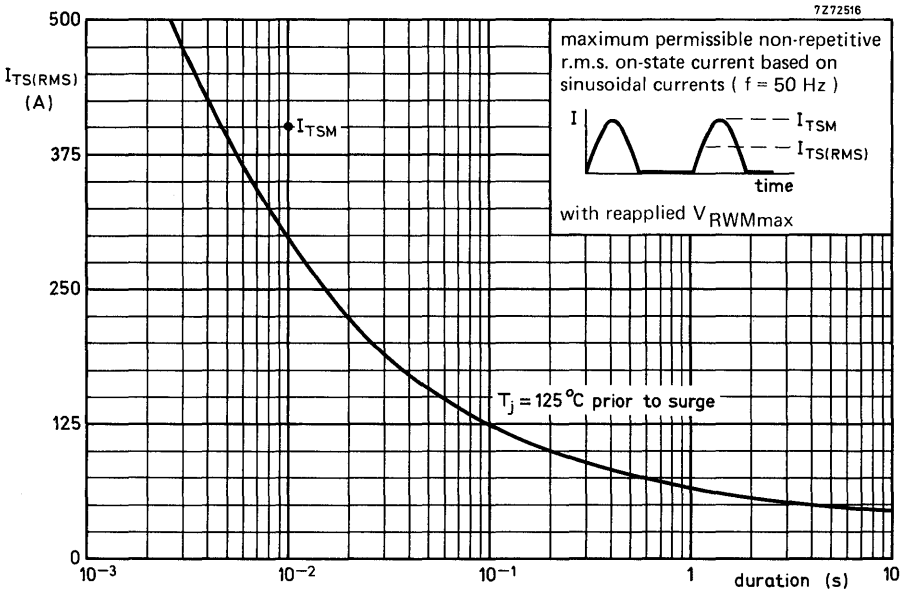


Fig. 3.

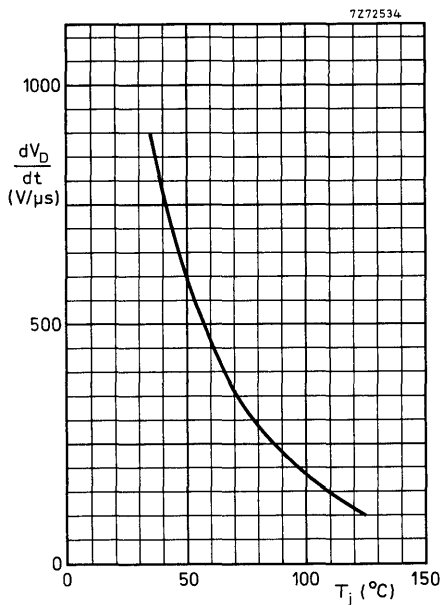


Fig. 4 Maximum rate of rise of off-state voltage that will not trigger any device (exponential method) as a function of T_j .

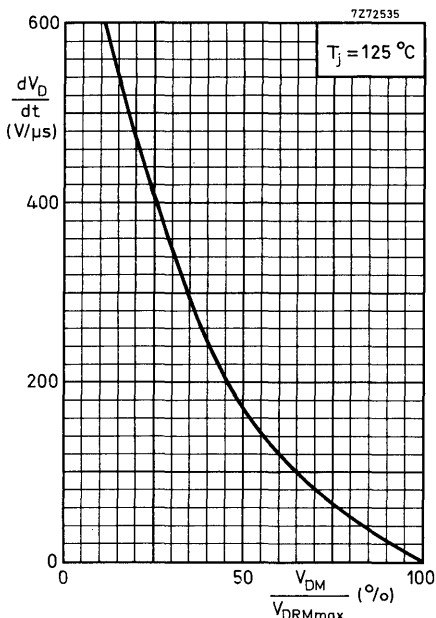


Fig. 5 Maximum rate of rise of off-state voltage that will not trigger any device (exponential method) as a function of applied voltage.

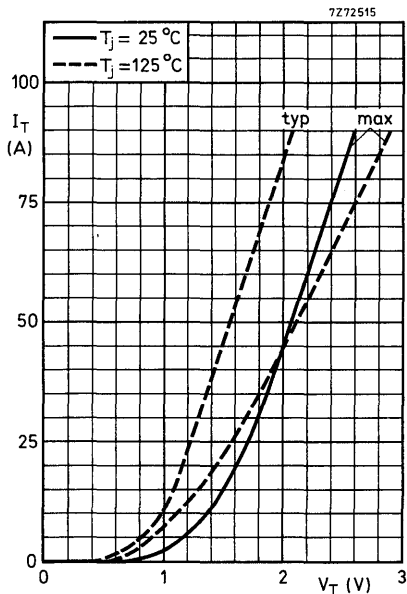


Fig. 6.

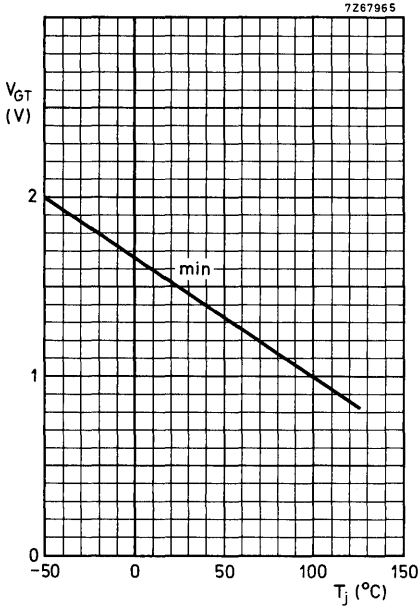


Fig. 7 Minimum gate voltage that will trigger all devices as a function of T_j .

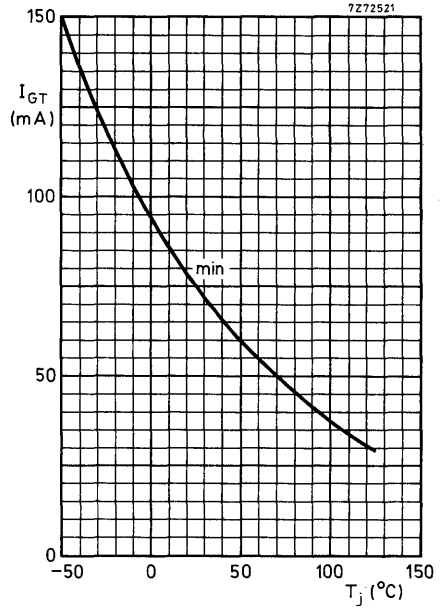


Fig. 8 Minimum gate current that will trigger all devices as a function of T_j .

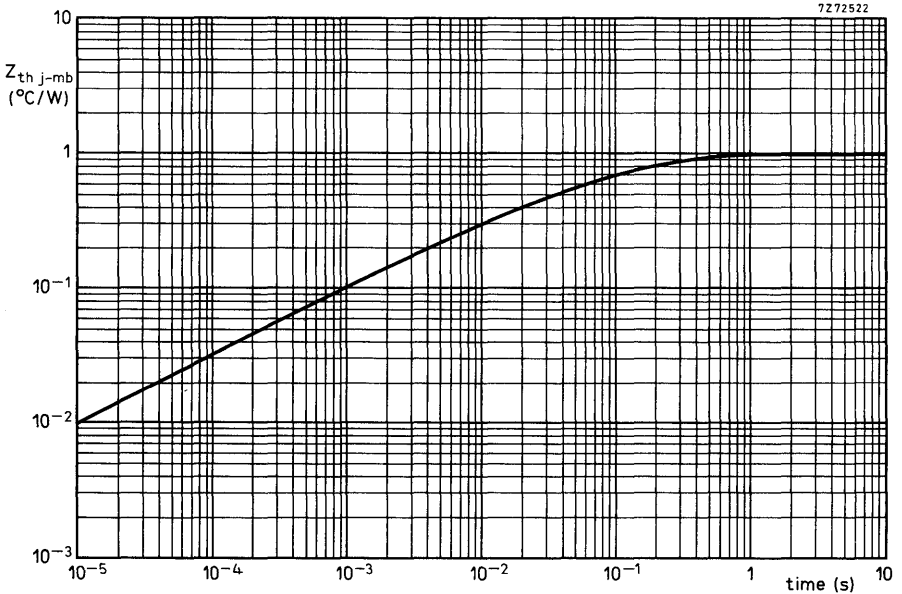


Fig. 9.